

# R1RP0408DI Series

Wide Temperature Range Version 4M High Speed SRAM (512-kword × 8-bit) R10DS0289EJ0100 Rev.1.00 Nov.18.19

### **Description**

The R1RP0408DI is a 4-Mbit high speed static RAM organized 512-kword  $\times$  8-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. The R1RP0408DI is packaged in 400-mil 36-pin SOJ for high density surface mounting.

#### **Features**

• Single 5.0V supply: 5.0V ± 10%

Access time: 12ns (max)Completely static memory

No clock or timing strobe required

• Equal access and cycle times

• Directly TTL compatible

— All inputs and outputs

Operating current: 130mA (max)TTL standby current: 40mA (max)

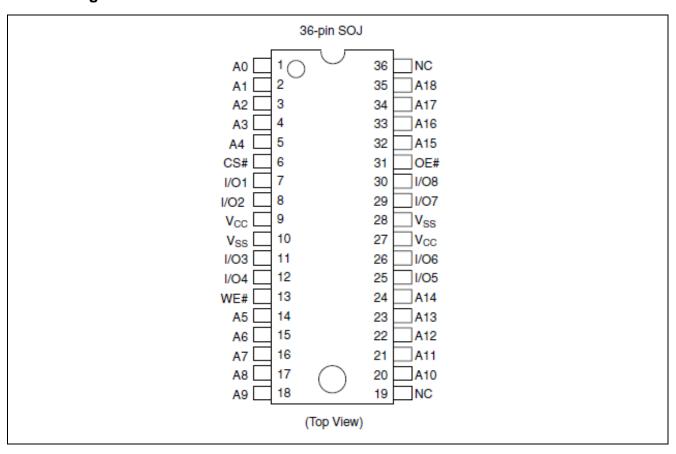
CMOS standby current : 5mA (max)
Center V<sub>CC</sub> and V<sub>SS</sub> type pin out

• Temperature range: -40 to +85°C

### **Ordering Information**

Type No.	Access time	Package
R1RP0408DGE-2PI	12ns	400-mil 36-pin plastic SOJ

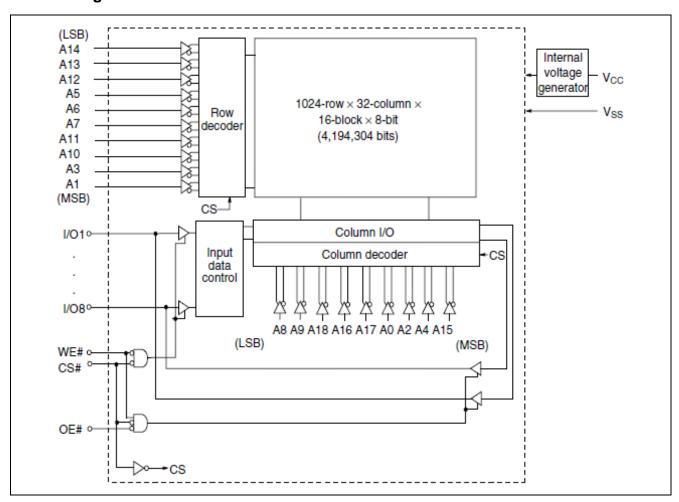
## **Pin Arrangement**



## **Pin Description**

Pin name	Function	
A0 to A18	Address input	
I/O1 to I/O8	Data input/output	
CS#	Chip select	
OE#	Output enable	
WE#	Write enable	
Vcc	Power supply	
Vss	Ground	
NC	No connection	

## **Block Diagram**



## **Operation Table**

CS#	OE#	WE#	Mode	Vcc current	I/O	Ref. cycle
Н	×	×	Standby	I <sub>SB</sub> , I <sub>SB1</sub>	High-Z	_
L	Н	Н	Output disable	Icc	High-Z	_
L	L	Н	Read	Icc	D <sub>OUT</sub>	Read cycle (1) to (3)
L	Н	L	Write	Icc	D <sub>IN</sub>	Write cycle (1)
L	L	L	Write	Icc	D <sub>IN</sub>	Write cycle (2)

Note: H: VIH, L: VIL, X: VIH or VIL

## **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Supply voltage relative to Vss	Vcc	−0.5 to +7.0	V
Voltage on any pin relative to V <sub>SS</sub>	V <sub>T</sub>	$-0.5^{*1}$ to $V_{CC} + 0.5^{*2}$	V
Power dissipation	P <sub>T</sub>	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	−55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  (min) = -2.0V for pulse width (under shoot)  $\leq$  6ns.

2.  $V_T$  (max) =  $V_{CC}$  + 2.0V for pulse width (over shoot)  $\leq$  6ns.

## **Recommended DC Operating Conditions**

 $(Ta = -40 \text{ to } +85^{\circ}C)$ 

				`	,
Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	Vcc*3	4.5	5.0	5.5	V
	Vss*4	0	0	0	V
Input voltage	ViH	2.0	_	Vcc + 0.5*2	V
	VIL	-0.5* <sup>1</sup>	_	0.8	V

Notes: 1.  $V_{IL}$  (min) = -2.0V for pulse width (under shoot)  $\leq$  6ns.

- 2.  $V_{IH}$  (max) =  $V_{CC}$  + 2.0V for pulse width (over shoot)  $\leq$  6ns.
- 3. The supply voltage with all  $V_{\text{CC}}$  pins must be on the same level.
- 4. The supply voltage with all  $V_{\text{SS}}$  pins must be on the same level.

## **DC Characteristics**

(Ta = -40 to  $+85^{\circ}$ C, V<sub>CC</sub> = 5.0V  $\pm$  10%, V<sub>SS</sub> = 0V)

Parameter	Symbol	Min	Max	Unit	Test conditions
Input leakage current	I <sub>LI </sub>	_	2	μΑ	$V_{IN} = V_{SS}$ to $V_{CC}$
Output leakage current	I <sub>LO </sub>	_	2	μΑ	$V_{IN} = V_{SS}$ to $V_{CC}$
Operating power supply current	Icc	_	130	mA	Min cycle CS# = V <sub>IL</sub> , I <sub>OUT</sub> = 0mA Other inputs = V <sub>IH</sub> /V <sub>IL</sub>
Standby power supply current	I <sub>SB</sub>	_	40	mA	Min cycle, CS# = V <sub>IH</sub> , Other inputs = V <sub>IH</sub> /V <sub>IL</sub>
	I <sub>SB1</sub>	_	5	mA	
Output voltage	Vol	_	0.4	V	I <sub>OL</sub> = 8mA
	Vон	2.4	_	V	I <sub>OH</sub> = -4mA

## Capacitance

 $(Ta = +25^{\circ}C, f = 1.0MHz)$ 

Parameter	Symbol	Min	Max	Unit	Test conditions
Input capacitance*1	C <sub>IN</sub>	_	6	pF	$V_{IN} = 0V$
Input/output capacitance*1	C <sub>I/O</sub>	_	8	pF	$V_{I/O} = 0V$

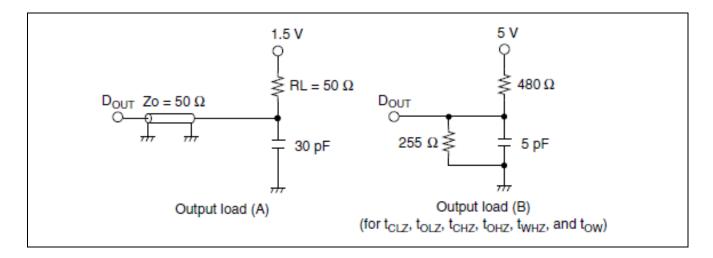
Note: 1. This parameter is sampled and not 100% tested.

#### **AC Characteristics**

**Test Conditions** (Ta = -40 to +85°C,  $V_{CC}$  =  $5.0V \pm 10\%$ , unless otherwise noted.)

Input pulse levels: 3.0V/0.0VInput rise and fall time: 3ns

Input and output timing reference levels: 1.5VOutput load: See figures (Including scope and jig)



### **Read Cycle**

		R1RP0408DI			
Parameter	Symbol	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	12	_	ns	
Address access time	t <sub>AA</sub>	_	12	ns	
Chip select access time	t <sub>ACS</sub>	_	12	ns	
Output enable to output valid	toE	_	6	ns	
Output hold from address change	tон	3	_	ns	
Chip select to output in low-Z	tclz	3	_	ns	1
Output enable to output in low-Z	tolz	0	_	ns	1
Chip deselect to output in high-Z	tснz	_	6	ns	1
Output disable to output in high-Z	tонz	_	6	ns	1

#### **Write Cycle**

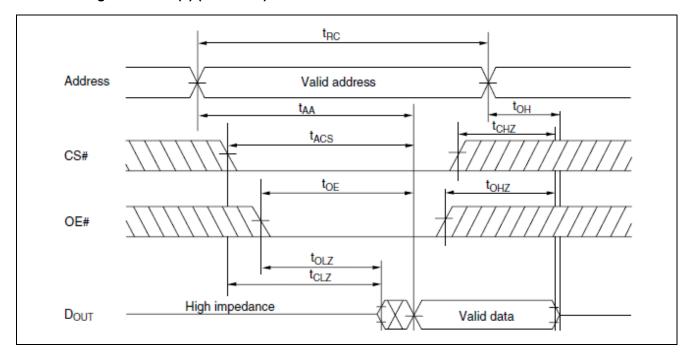
	R1RP0408DI				
Parameter	Symbol	Min	Max	Unit	Notes
Write cycle time	t <sub>WC</sub>	12	_	ns	
Address valid to end of write	t <sub>AW</sub>	8	_	ns	
Chip select to end of write	tcw	8	_	ns	9
Write pulse width	twp	8	_	ns	8
Address setup time	t <sub>AS</sub>	0	_	ns	6
Write recovery time	twR	0	_	ns	7
Data to write time overlap	t <sub>DW</sub>	6	_	ns	
Data hold from write time	tон	0	_	ns	
Write disable to output in low-Z	tow	3	_	ns	1
Output disable to output in high-Z	tонz	_	6	ns	1
Write enable to output in high-Z	t <sub>WHZ</sub>	_	6	ns	1

Notes: 1. Transition is measured  $\pm 200 \text{mV}$  from steady voltage with output load (B). This parameter is sampled and not 100% tested.

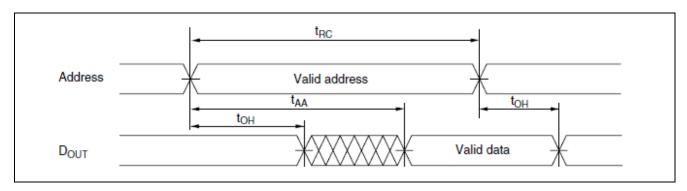
- 2. Address should be valid prior to or coincident with CS# transition low.
- 3. WE# and/or CS# must be high during address transition time.
- 4. If CS# and OE# are low during this period, I/O pins are in the output state. Then, the data input signals of opposite phase to the outputs must not be applied to them.
- 5. If the CS# low transition occurs simultaneously with the WE# low transition or after the WE# transition, output remains a high impedance state.
- 6. t<sub>AS</sub> is measured from the latest address transition to the later of CS# or WE# going low.
- 7. twR is measured from the earlier of CS# or WE# going high to the first address transition.
- 8. A write occurs during the overlap of a low CS# and a low WE#. A write begins at the latest transition among CS# going low and WE# going low. A write ends at the earliest transition among CS# going high and WE# going high. twp is measured from the beginning of write to the end of write.
- 9. t<sub>CW</sub> is measured from the later of CS# going low to the end of write.

## **Timing Waveforms**

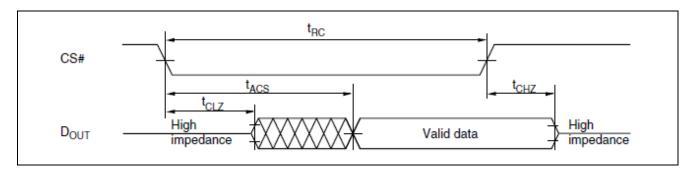
## Read Timing Waveform (1) (WE# = $V_{IH}$ )



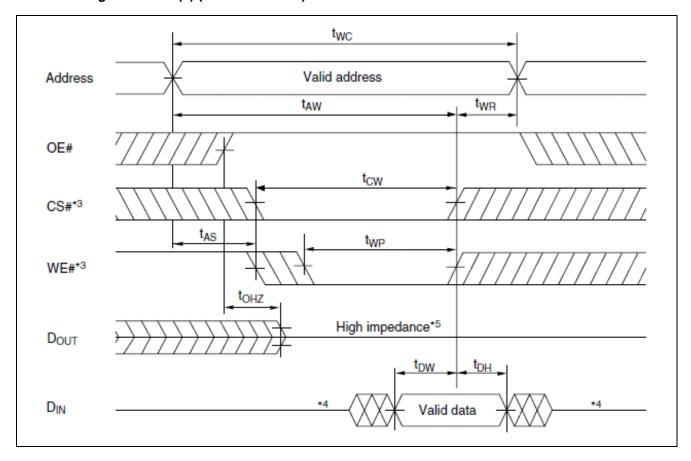
### Read Timing Waveform (2) (WE# = $V_{IH}$ , LB# = $V_{IL}$ , UB# = $V_{IL}$ )



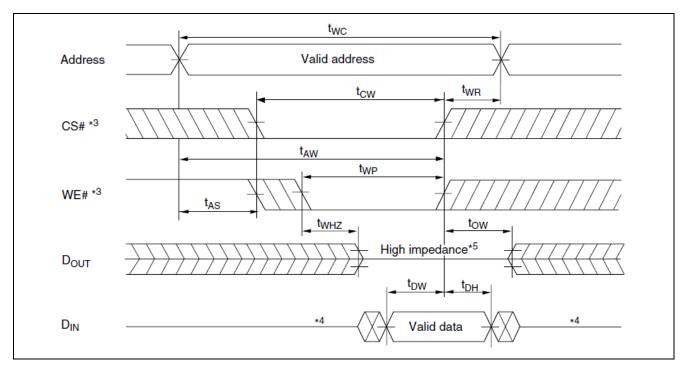
## Read Timing Waveform (3) (WE# = $V_{IH}$ , CS# = $V_{IL}$ , OE# = $V_{IL}$ )\*2



## Write Timing Waveform (1) (WE# Controlled)



### Write Timing Waveform (2) (CS# Controlled)



## **Revision History**

			Description					
Rev.	Date	Page Summary						
1.00	Nov.18.19	-	First Edition issued					

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TOYOSU FORESIA, 3-2-24 Toyosu, Koto-ku, Tokyo 135-0061, Japan www.renesas.com

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